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Advanced Probe Card and Method of Fabricating Same

Inventors: Bo Jin, et al.

Atty Docket No. 10002.003010 (CD03002)

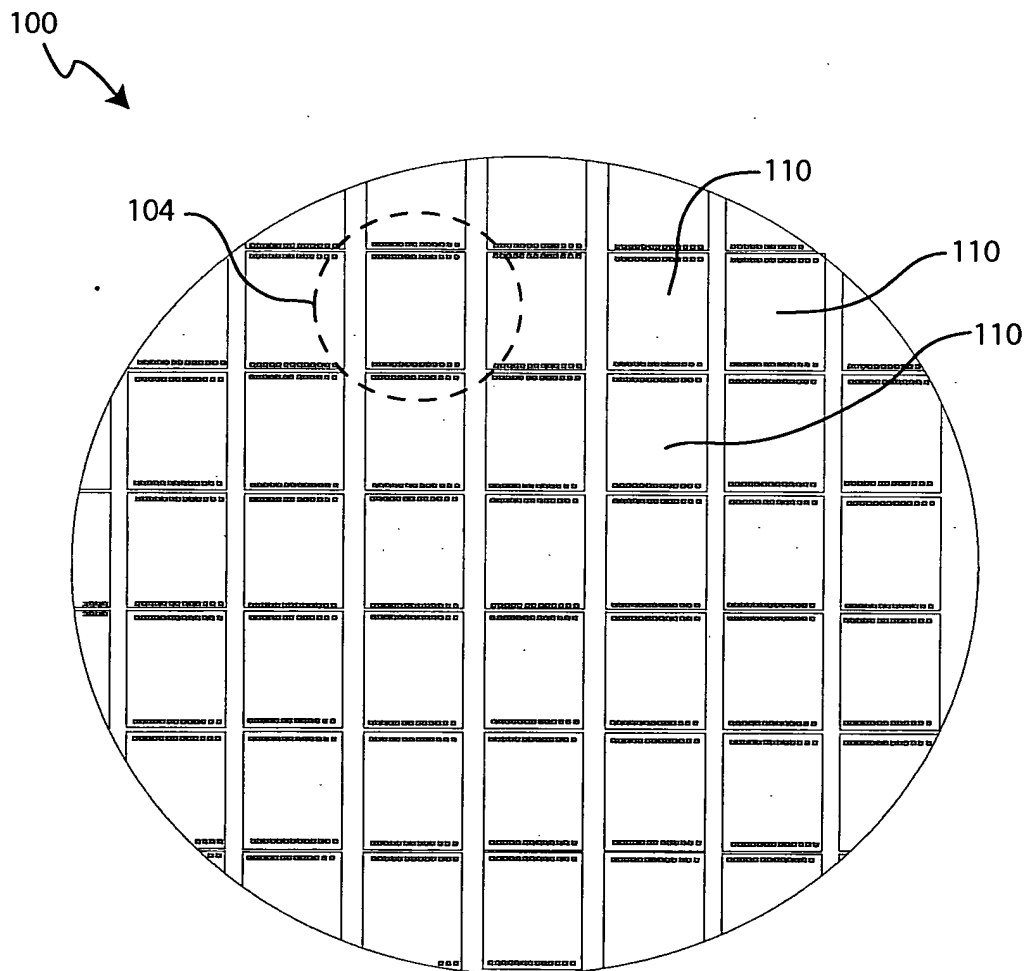


FIG. 1

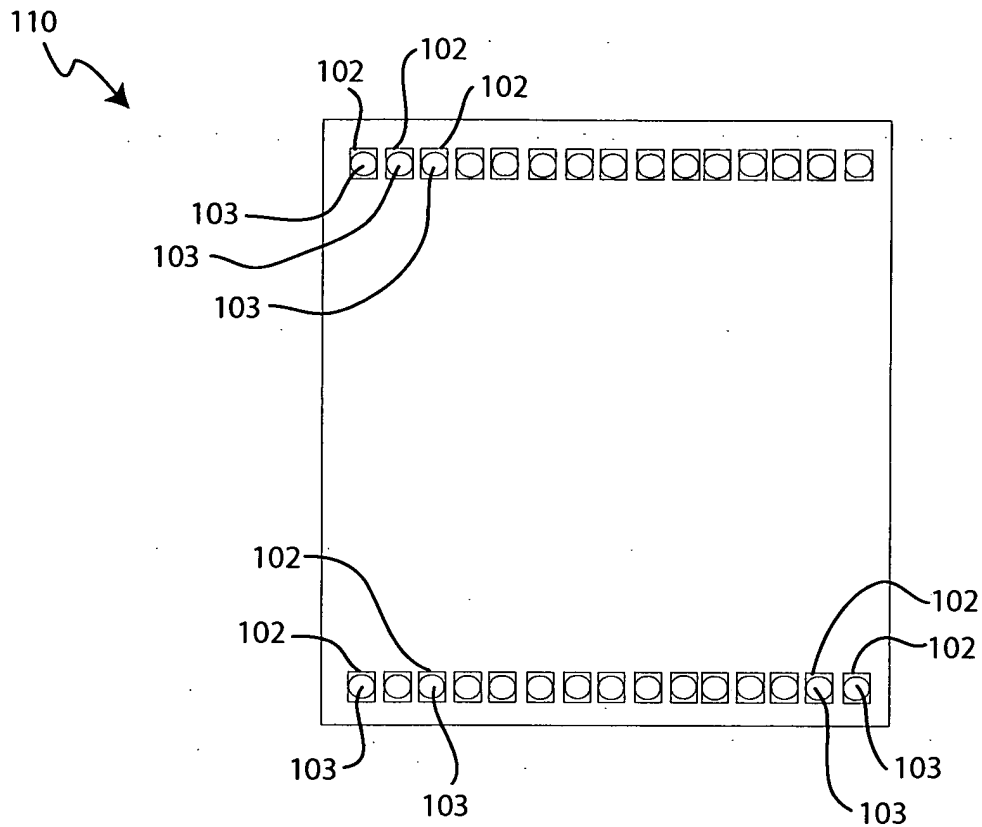


FIG. 2

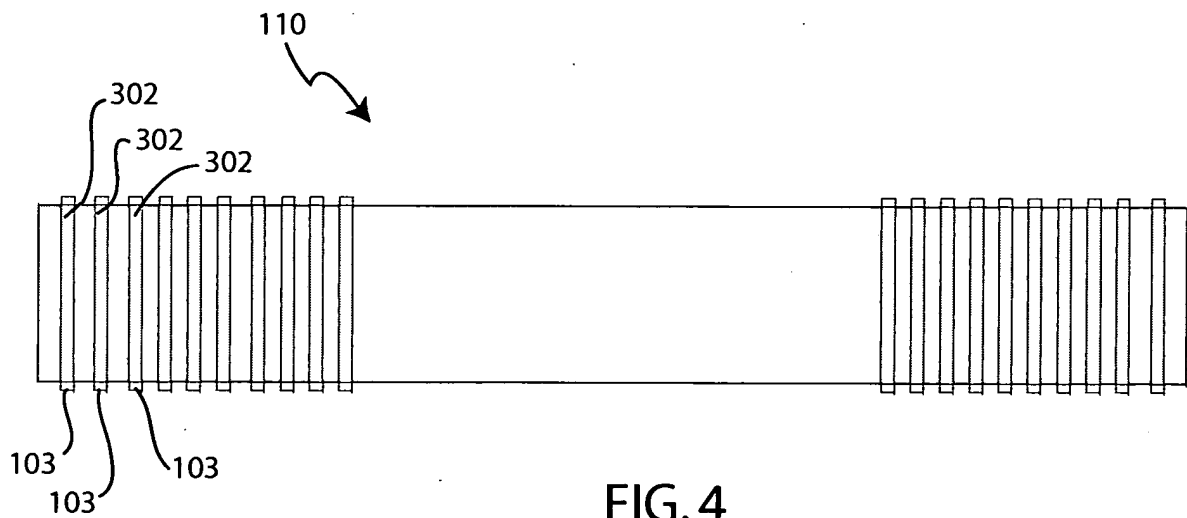


FIG. 4



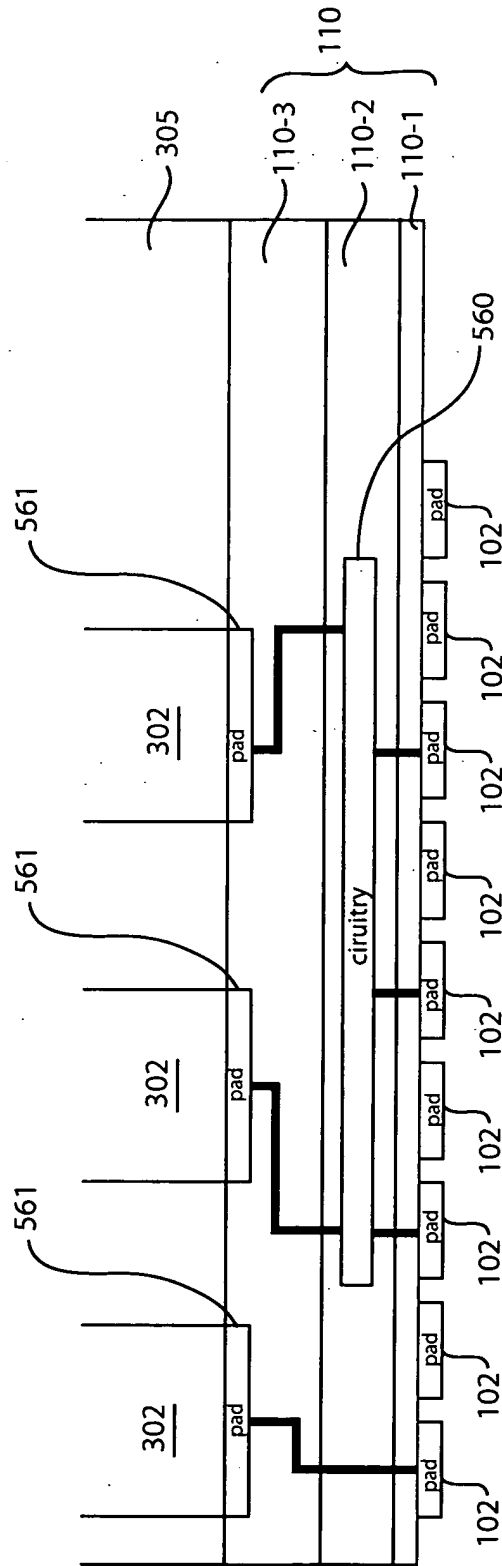


FIG. 5

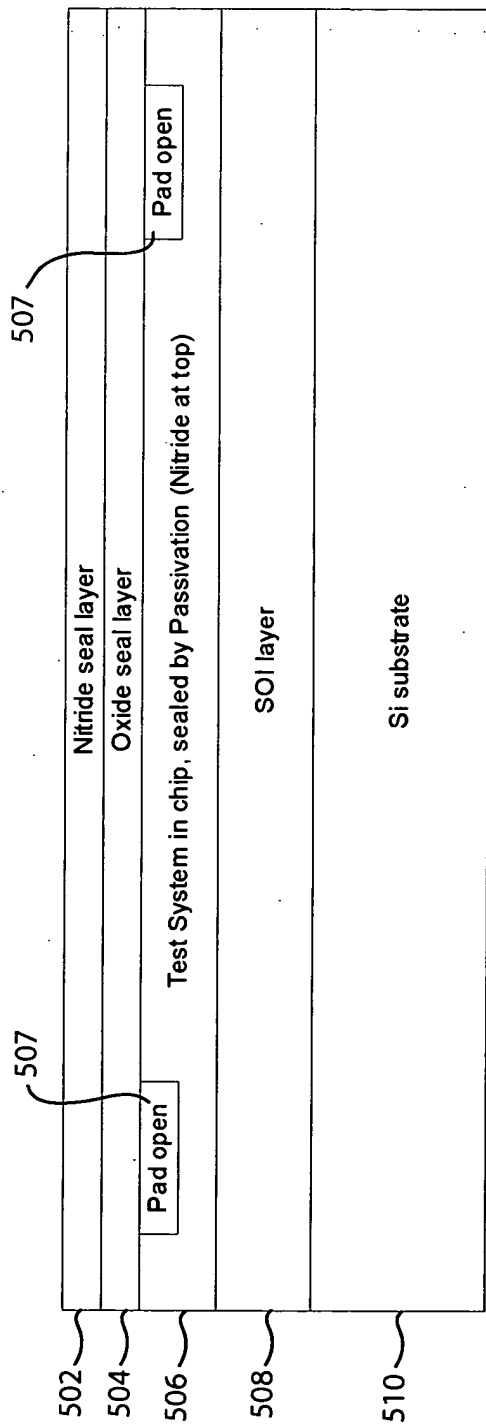


FIG. 6

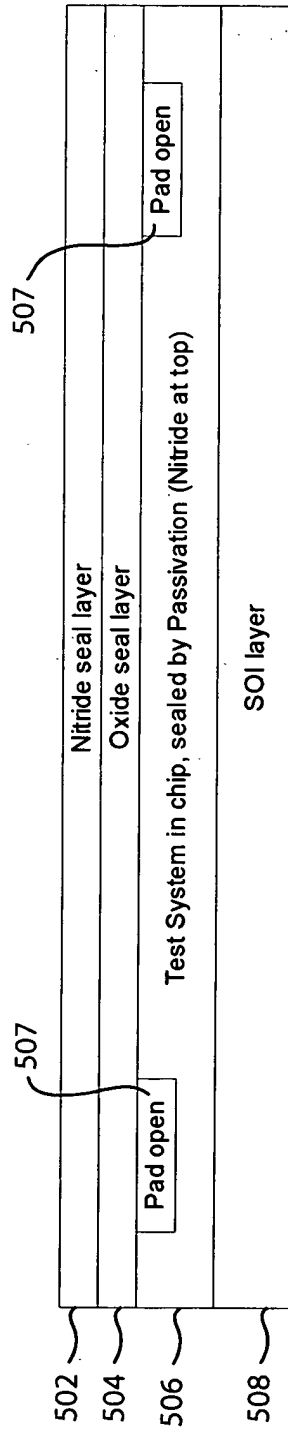


FIG. 7

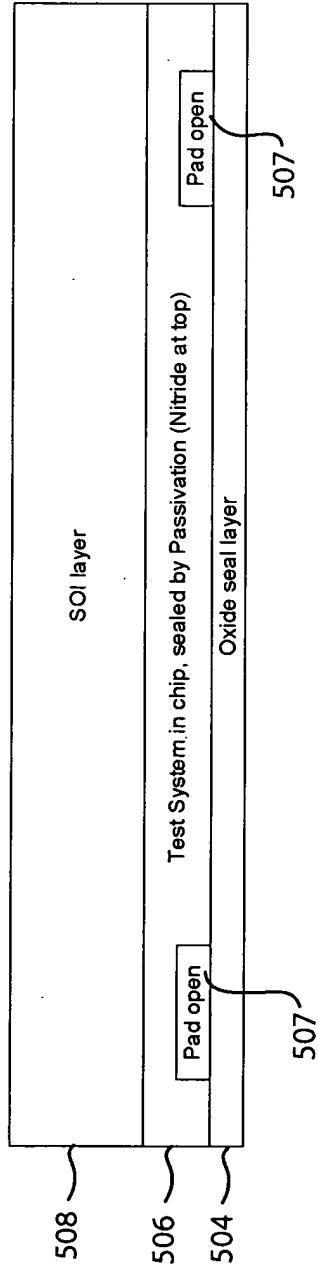


FIG. 8

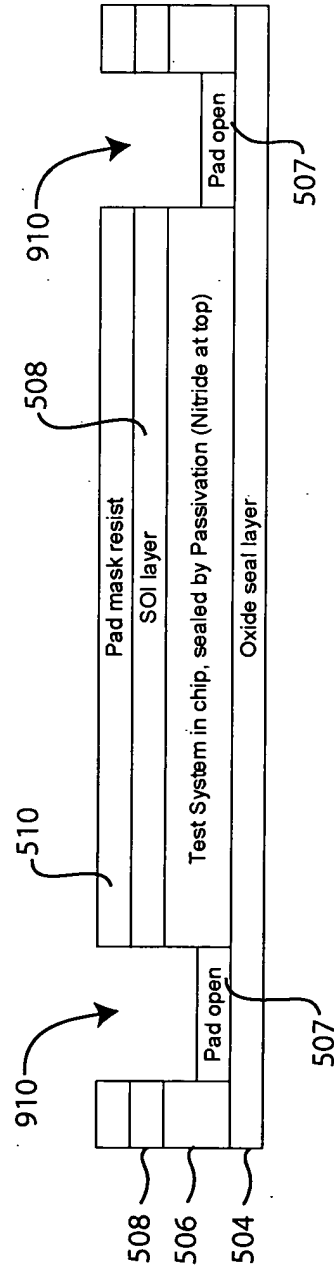


FIG. 9

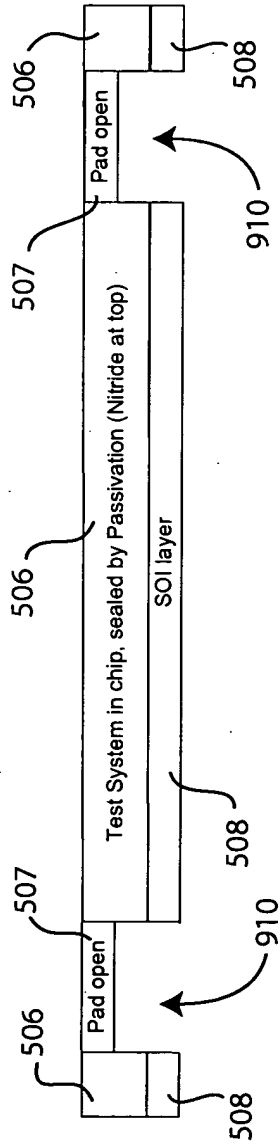


FIG. 10

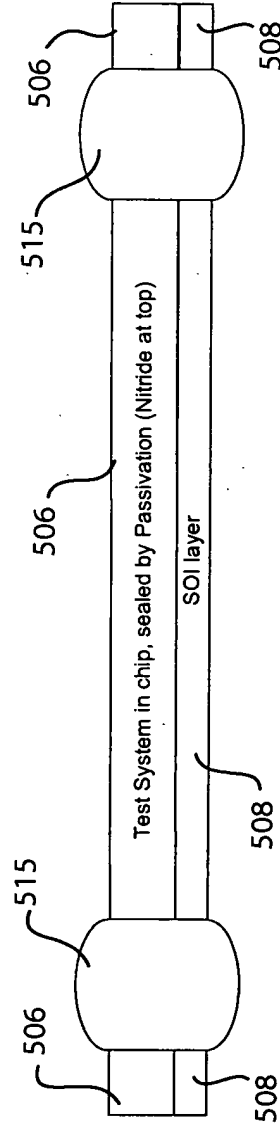


FIG. 11